

# Self-consistent modelling of particle-reflection-distributions of rough surfaces



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## ABSTRACT

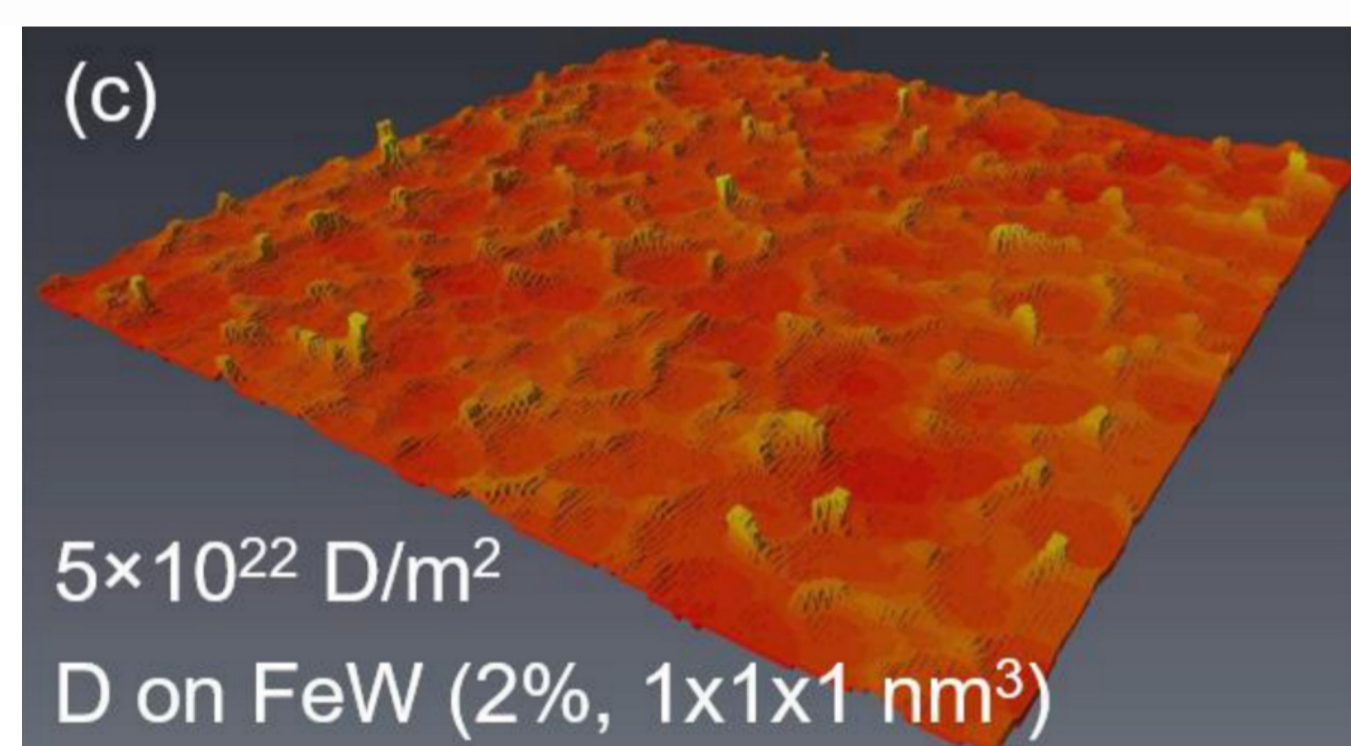
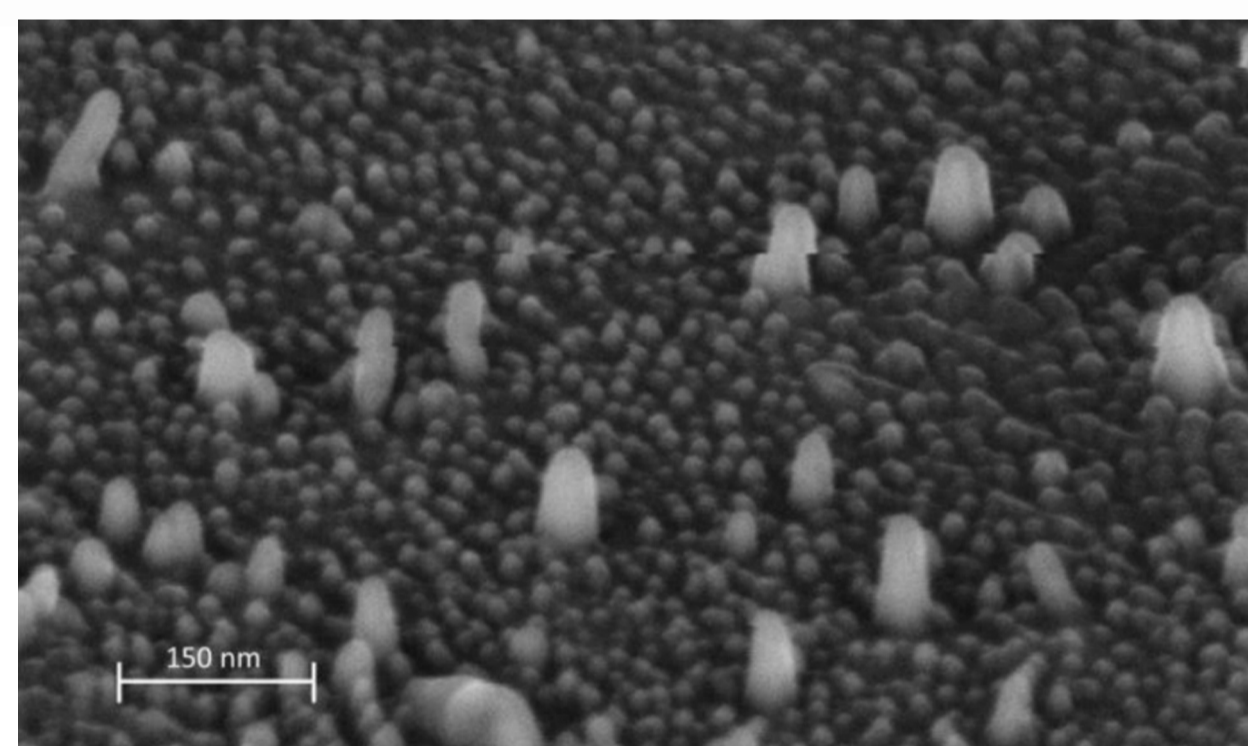
- Modelling of Plasma-Wall-Interactions (PWI) depends on distributions describing the angle- and energy distribution of particles scattered at first wall  $R(\rho, \theta, E | E_0, \phi_0, \theta_0, S)$
- Most PWI codes (like SOLPS, EIRENE) rely on extensive tables based on reflection simulations (e.g. by SDTrimSP-1D) or analytical formulae – however, both approaches assume an atomistically flat (smooth) surface
- Rough surfaces which are formed under particle impact typically display a **very different particle distribution** compared to smooth surfaces [1] – also the differences are much larger compared to the effects on sputter yields
- Roughening almost unavoidable e.g. due to preferential sputtering, crystal-orientation dependent sputtering, precipitates, thermal cycling [2]
- The effects of roughening on the reflection distributions have been investigated using W- and W-Fe-surfaces of different morphology with molecular dynamics (LAMMPS) and within the binary collision approximation (BCA) by SDTrimSP-2D

## MODELLING APPROACH

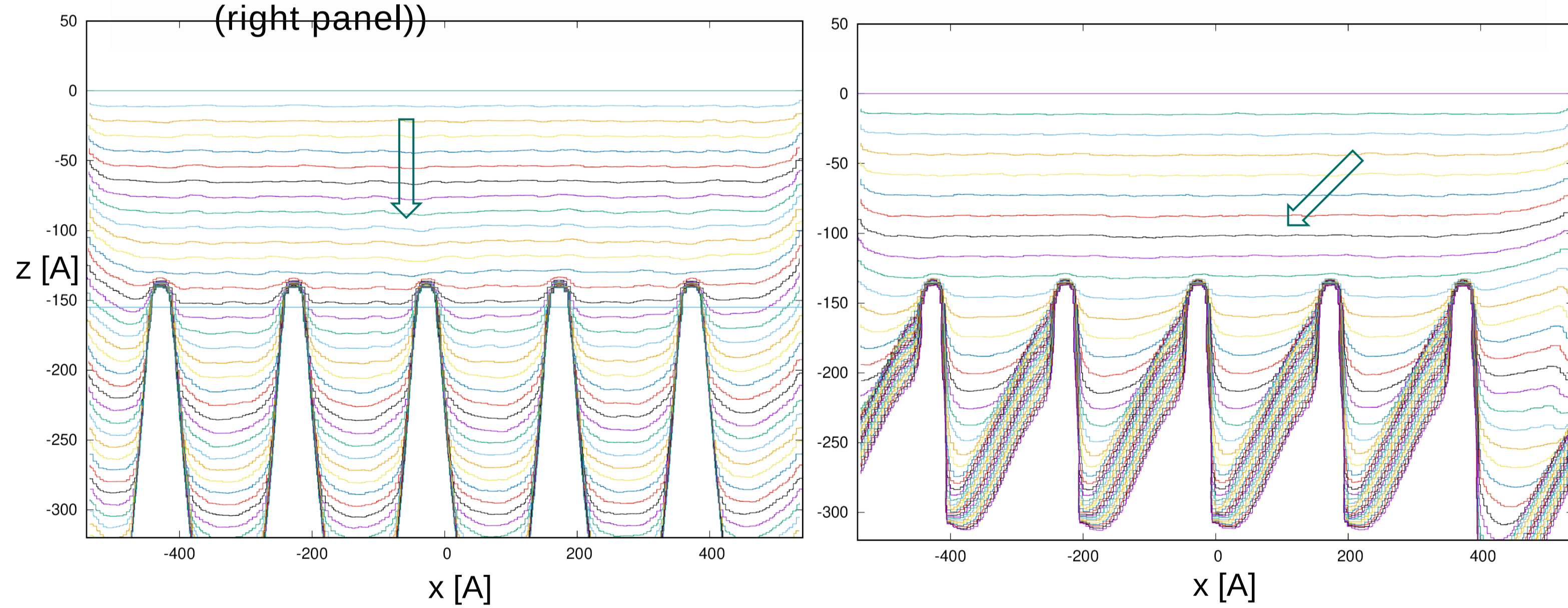
- Dynamic surface evolution under ion-irradiation has been modelled using SDTrimSP-2D (version 2.06)
- Determination of reflection distributions at various fluence steps keeping the surface unchanged (static mode)
- Molecular dynamic simulations are performed with LAMMPS using the Tersoff-type potential by Juslin [3] for the WH-system
- SDTrimSP 7.00 for BCA-type simulations using a W-bcc-lattice at 700 K
- Data compression using **hemi-spherical** harmonic basis functions  $Y_m^l$  [4] for  $R(\rho, \theta | E_i, E_0, \phi_0, \theta_0, S)$  followed by a Chebyshev-series for the individual  $Y_m^l(E_i)$  as function of  $E_i$

## DYNAMIC SURFACE EVOLUTION

- Example of EUROFER and surrogate (2%W in Fe) [5] under ion-irradiation with 200 eV D left: SEM-image right: simulation with SDTrimSP-3D

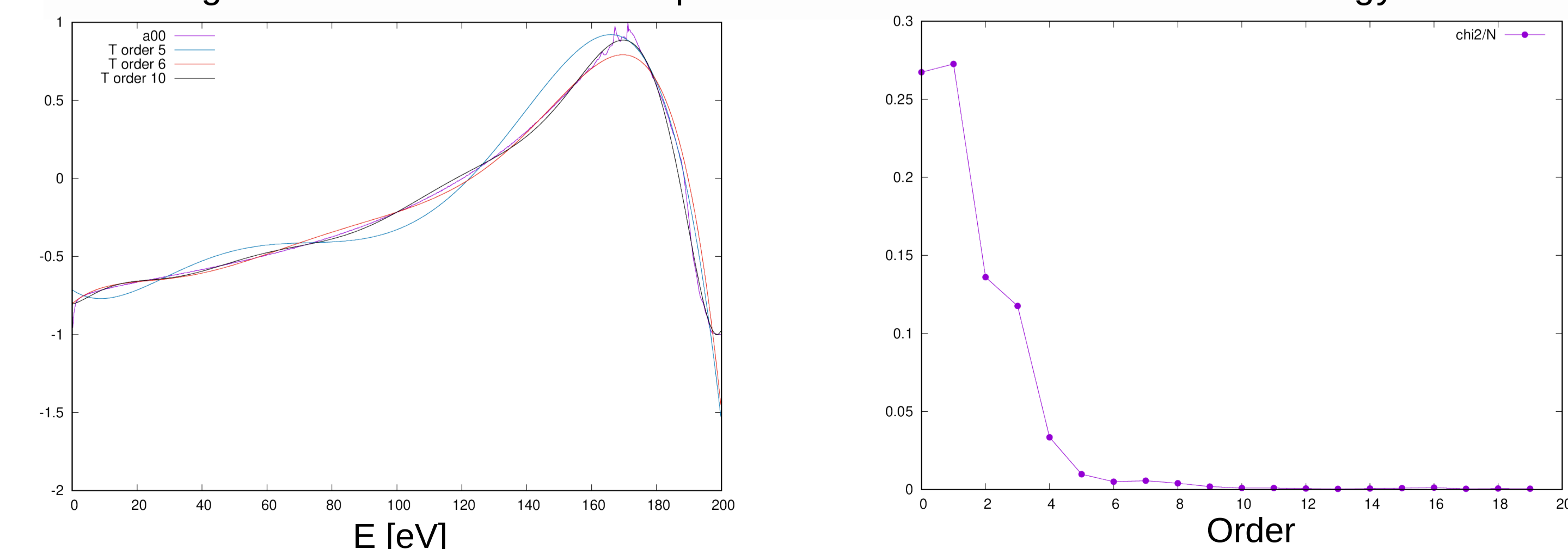


- Focus on simplified model-system with 2d-periodic structure (Fe with embedded tungsten pillars) : surface erosion under 200 eV D bombardment for two different angles (perpendicular impact ( $\theta = 0$  deg) (left panel) and  $\theta = 45$  deg (right panel))



## DATA COMPRESSION USING A NEW BASIS SYSTEM

- 3-dimensional distributions are impractical to handle by tables and coarse graining possibilities are limited use of hemispherical orthonormal basis for angular distribution and interpolate coefficients as function of energy

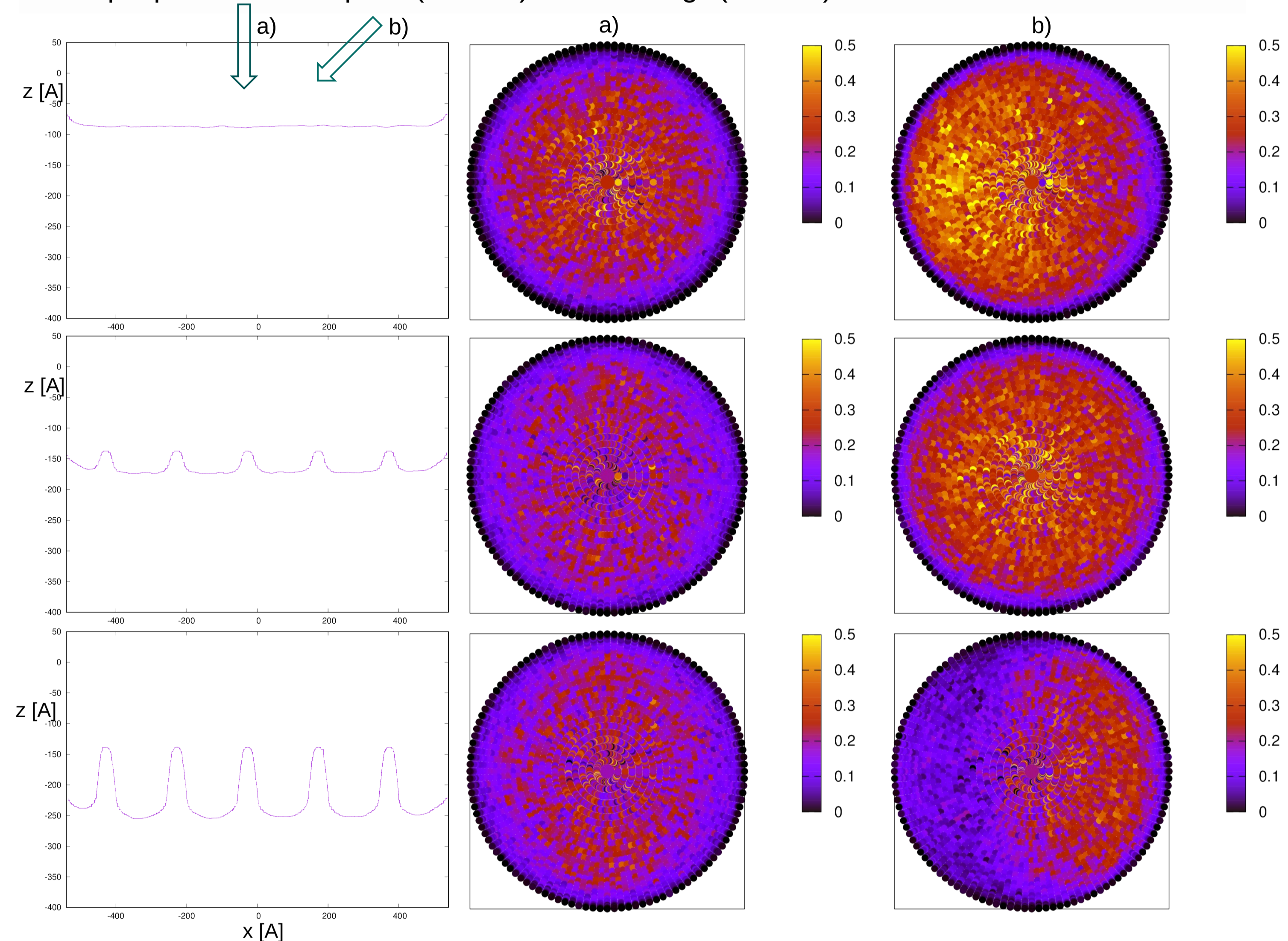


## CONCLUSION

- Reflection properties of surfaces are much *stronger affected* by surface morphologies (ie. roughness) than sputter yields
- A robust result is the **strong attenuation** of the often assumed specular (forward) reflection of non-perpendicular impinging particles – typically most pronounced for the reflected particles with the highest energies. In some structures even **backward-reflection** may become **dominant** : consequences on PWI-modelling results need to be assessed
- Effect is present in amorphous and crystalline samples
- Efficient tabulation of data (particle-reflection distribution function  $R(\rho, \theta, E | E_0, (\phi_0), \theta_0, S)$ ) for PWI-codes appears feasible using a suitable orthogonal basis-function system
- Dynamically evolving 3-d morphologies are feasible - but computationally still **very heavy** : put focus on reference surfaces?

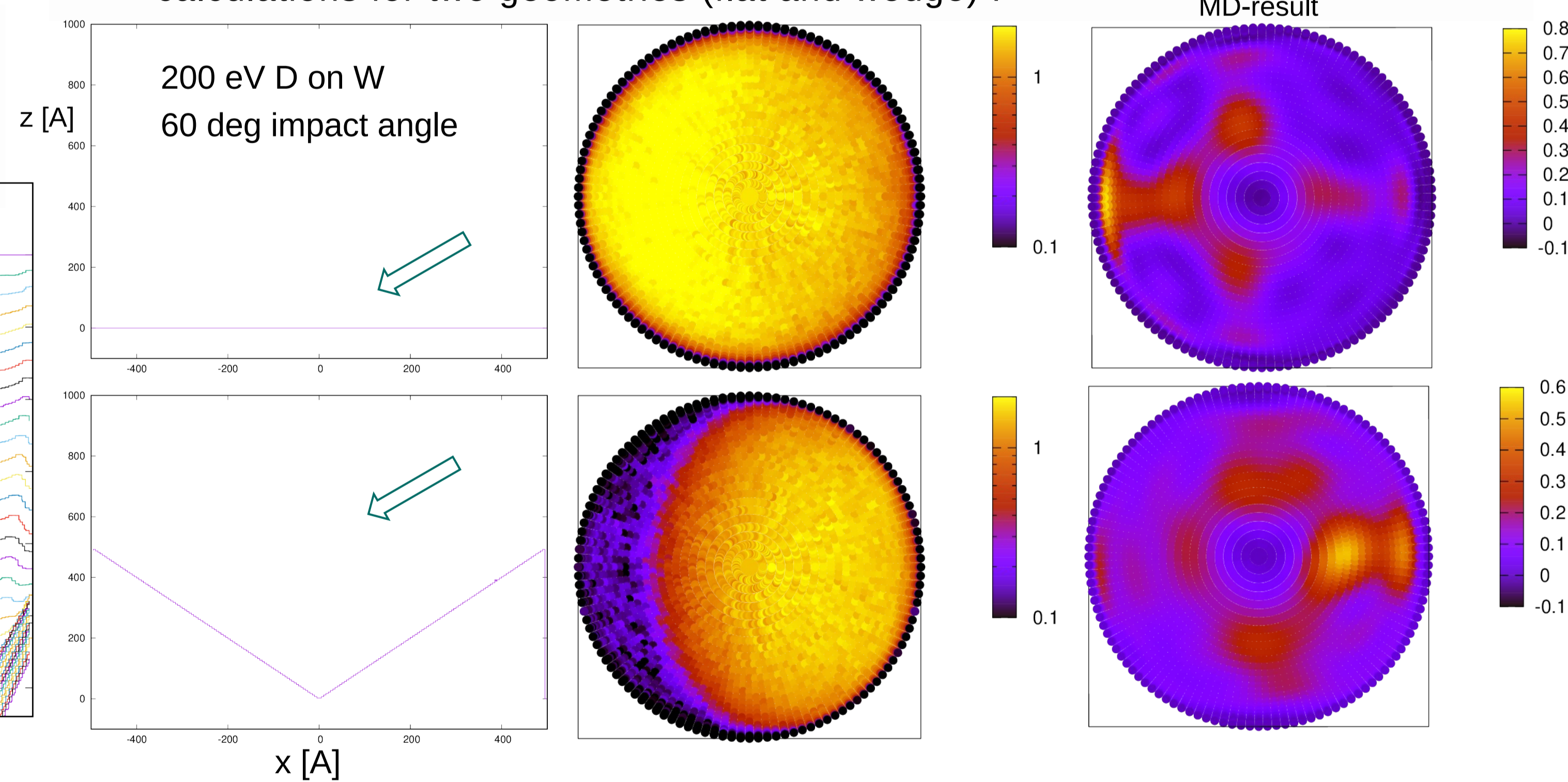
## MODELLING RESULTS I

- $(\phi-\theta)$ -polar plots of reflected particle distributions ( $\phi=[0..360]$  deg,  $\theta=[0..90]$  deg), perpendicular impact (case a) and 45 deg (case b)



## MODELLING RESULTS II

- Comparison of (amorphous) SDTrimSP-simulations with (crystalline) MD-calculations for two geometries (flat and wedge) :



- Example: reflection of 200 eV D impinging under 45 degrees onto tungsten : angular distribution for D atoms reflected with  $E_r = 164$  eV: particle histogram (left panel), series coefficients of Y-expansion (middle panel), derived density (right panel)

